



10-31-00

A

Please type a plus sign (+) inside this box →

PTO/SB/05 (4/98)

Approved for use through 09/30/2000. OMB 0651-0032

Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

UTILITY PATENT APPLICATION TRANSMITTAL

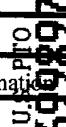
(Only for new nonprovisional applications under 37 C.F.R. § 1.53(b))

Attorney Docket No. H0001190(4016)

First Inventor or Application Identifier Matthew S. Cooper

Title Physical Vapor Deposition Components and Methods of Formation

Express Mail Label No. EL465852649US



10/27/00

APPLICATION ELEMENTS

See MPEP chapter 600 concerning utility patent application contents.

1. * Fee Transmittal Form (e.g., PTO/SB/17)
(Submit an original and a duplicate for fee processing)
2. Specification [Total Pages 21]
 - Descriptive title of the Invention
 - Cross References to Related Applications
 - Statement Regarding Fed sponsored R & D
 - Reference to Microfiche Appendix
 - Background of the Invention
 - Brief Summary of the Invention
 - Brief Description of the Drawings (if filed)
 - Detailed Description
 - Claim(s)
 - Abstract of the Disclosure
3. Drawing(s) (35 U.S.C. 113) [Total Sheets 1]
4. Oath or Declaration [Total Pages 3]
 - a. Newly executed (original or copy)
 - b. Copy from a prior application (37 C.F.R. § 1.63(d)) (for continuation/divisional with Box 16 completed)
 - i. DELETION OF INVENTOR(S)
Signed statement attached deleting inventor(s) named in the prior application, see 37 C.F.R. §§ 1.63(d)(2) and 1.33(b).

* NOTE FOR ITEMS 1 & 13 IN ORDER TO BE ENTITLED TO PAY SMALL ENTITY FEES, A SMALL ENTITY STATEMENT IS REQUIRED (37 C.F.R. § 1.27), EXCEPT IF ONE FILED IN A PRIOR APPLICATION IS RELIED UPON (37 C.F.R. § 1.28).

ADDRESS TO: Assistant Commissioner for Patents
Box Patent Application
Washington, DC 20231

5. Microfiche Computer Program (Appendix)
6. Nucleotide and/or Amino Acid Sequence Submission (if applicable, all necessary)
 - a. Computer Readable Copy
 - b. Paper Copy (identical to computer copy)
 - c. Statement verifying identity of above copies

ACCOMPANYING APPLICATION PARTS

7. Assignment Papers (cover sheet & document(s))
8. 37 C.F.R. § 3.73(b) Statement Power of (when there is an assignee) Attorney
9. English Translation Document (if applicable)
10. Information Disclosure Statement (IDS)/PTO-1449 Copies of IDS Citations
11. Preliminary Amendment
12. Return Receipt Postcard (MPEP 503) (Should be specifically itemized)
13. * Small Entity Statement(s) Statement filed in prior application (PTO/SB/09-12) Status still proper and desired
14. Certified Copy of Priority Document(s) (if foreign priority is claimed)
15. Other: Check in the amount of \$1224.00.

16. If a CONTINUING APPLICATION, check appropriate box, and supply the requisite information below and in a preliminary amendment:

Continuation Divisional Continuation-in-part (CIP) of prior application No: /

Prior application information: Examiner

Group / Art Unit:

For CONTINUATION or DIVISIONAL APPS only: The entire disclosure of the prior application, from which an oath or declaration is supplied under Box 4b, is considered a part of the disclosure of the accompanying continuation or divisional application and is hereby incorporated by reference. The incorporation can only be relied upon when a portion has been inadvertently omitted from the submitted application parts.

17. CORRESPONDENCE ADDRESS

Customer Number or Bar Code Label (Insert Customer No. or Attach bar code label here) or Correspondence address below

Name	Shannon Morris		
	Honeywell International Inc.		
Address	PO Box 2245		
	Law Dept. AB2, 101 Columbia Road		
City	Morristown	State	NJ
Country		Telephone	(724) 452-1300
			Fax (724) 452-7703

Name (Print/Type)	James E. Lake	Registration No. (Attorney/Agent)	44,854
-------------------	---------------	-----------------------------------	--------

Signature		Date	27 Oct 00
-----------	--	------	-----------

Burden Hour Statement: This form is estimated to take 0.2 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, Box Patent Application, Washington, DC 20231.

EL465852649US

FEE TRANSMITTAL

for FY 1999

Patent fees are subject to annual revision.

Small Entity payments must be supported by a small entity statement, otherwise large entity fees must be paid. See Forms PTO/SB/09-12.

TOTAL AMOUNT OF PAYMENT (\$1224.00)

Complete if Known

Application Number	Unknown
Filing Date	Herewith (10/27/00)
First Named Inventor	Matthew S. Cooper
Examiner Name	Unassigned
Group / Art Unit	Unassigned
Attorney Docket No.	H0001190(4016)

METHOD OF PAYMENT (check one)

1. The Commissioner is hereby authorized to charge indicated fees and credit any over payments to:

Deposit Account Number: 23-0925
Deposit Account Name: Wells, St. John

Charge Any Additional Fee Required Under 37 CFR 1.16 and 1.17

2. Payment Enclosed:

Check Money Order Other

FEE CALCULATION

1. BASIC FILING FEE

Large Entity Fee Code (\$)	Small Entity Fee Code (\$)	Fee Description	Fee Paid
101	760	201 380 Utility filing fee	710.00
106	310	206 155 Design filing fee	
107	480	207 240 Plant filing fee	
108	760	208 380 Reissue filing fee	
114	150	214 75 Provisional filing fee	
SUBTOTAL (1) (\$)			710.00

2. EXTRA CLAIM FEES

Total Claims	Extra Claims	Fee from below	Fee Paid
33	-20**=13	X 18.00	= 234.00
Independent Claims 6	-3***=3	X 80.00	= 240.00
Multiple Dependent			= 0.00

**or number previously paid, if greater. For Reissues, see below

Large Entity Fee Code (\$)	Small Entity Fee Code (\$)	Fee Description
103	18	203 9 Claims in excess of 20
102	78	202 39 Independent claims in excess of 3
104	260	204 130 Multiple dependent claim, if not paid
109	78	209 39 ** Reissue independent claims over original patent
110	18	210 9 ** Reissue claims in excess of 20 and over original patent
SUBTOTAL (2) (\$)		

474.00

3. ADDITIONAL FEES

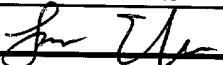
Large Entity Fee Code (\$)	Small Entity Fee Code (\$)	Fee Description	Fee Paid
105	130	205 65 Surcharge - late filing fee or oath	0.00
127	50	227 25 Surcharge - late provisional filing fee or cover sheet	0.00
139	130	139 130 Non-English specification	0.00
147	2,520	147 2,520 For filing a request for reexamination	0.00
112	920*	112 920* Requesting publication of SIR prior to Examiner action	0.00
113	1,840*	113 1,840* Requesting publication of SIR after Examiner action	0.00
115	110	215 55 Extension for reply within first month	0.00
116	380	216 190 Extension for reply within second month	0.00
117	870	217 435 Extension for reply within third month	0.00
118	1,360	218 680 Extension for reply within fourth month	0.00
128	1,850	228 925 Extension for reply within fifth month	0.00
119	300	219 150 Notice of Appeal	0.00
120	300	220 150 Filing a brief in support of an appeal	0.00
121	260	221 130 Request for oral hearing	0.00
138	1,510	138 1,510 Petition to institute a public use proceeding	0.00
140	110	240 55 Petition to revive - unavoidable	0.00
141	1,210	241 605 Petition to revive - unintentional	0.00
142	1,210	242 605 Utility issue fee (or reissue)	0.00
143	430	243 215 Design issue fee	0.00
144	580	244 290 Plant issue fee	0.00
122	130	122 130 Petitions to the Commissioner	0.00
123	50	123 50 Petitions related to provisional applications	0.00
126	240	126 240 Submission of Information Disclosure Stmt	0.00
581	40	581 40 Recording each patent assignment per property (times number of properties)	0.00
146	760	246 380 Filing a submission after final rejection (37 CFR 1.129(a))	40.00
149	760	249 380 For each additional invention to be examined (37 CFR 1.129(b))	0.00
Other fee (specify) _____			0.00
Other fee (specify) _____			0.00

*Reduced by Basic Filing Fee Paid

SUBTOTAL (3) (\$)

40.00

SUBMITTED BY

Typed or Printed Name	James E. Lake	Complete (if applicable)
Signature		Reg. Number 44,854 Deposit Account User ID

Burden Hour Statement: This form is estimated to take 0.2 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, Washington, DC 20231

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICATION FOR LETTERS PATENT

* * * * *

**Physical Vapor Deposition Components and Methods of
Formation**

* * * * *

INVENTOR

Matthew S. Cooper

ATTORNEY'S DOCKET NO. H0001190(4016)

Physical Vapor Deposition Components and Methods of Formation

TECHNICAL FIELD

The invention relates to physical vapor deposition (PVD) components, for 5 example, sputter targets, and methods of forming PVD components and sputter targets, including magnetic flux enhancement methods for PVD components.

BACKGROUND OF THE INVENTION

Sputtering is a common physical vapor deposition (PVD) process used often 10 in semiconductor processing as well as other processing and fabrication. The properties of a PVD component, such as a target, impose varying effects on properties exhibited by a deposited film. Grain size is known to influence deposited film uniformity and is preferably less than about 100 microns. Further, as grain size increases, a phenomenon known as secondary re-crystallization can be observed 15 wherein isolated domains of extremely large grains (greater than about 200 microns) appear in a component material. Secondary re-crystallization can also be detrimental to deposited film uniformity. Other properties of a component material may effect deposited film uniformity and limit target life as well.

Accordingly, a need exists to reduce grain size of sputtering targets and 20 identify material properties beneficial to forming deposited films and prolonging target life.

SUMMARY OF THE INVENTION

In one aspect of the invention, a PVD component forming method includes

inducing a sufficient amount of stress in the component to increase magnetic pass through flux exhibited by the component compared to pass through flux exhibited prior to inducing the stress. The method may further include orienting a majority crystallographic structure of the component at (200) prior to inducing the stress,

5 wherein the induced stress alone is not sufficient to substantially alter surface grain appearance.

In another aspect of the invention, a physical vapor deposition (PVD) component forming method includes first cold working a component blank to at least about an 80% reduction in cross-sectional area. The cold worked component

10 blank may be heat treated at least at about a minimum recrystallization temperature of the component blank and second cold worked to a reduction in cross-sectional area between about 5% to about 15% of the heat treated component. By way of example, at least one of the first and second cold working can comprise cold rolling. The component blank can consist essentially of nickel. At least one of the first and

15 second cold working can be unidirectional and the heat treating may be performed with a fluidized bed furnace. Also, the heat treating can include substantially uniformly heating the cold worked component blank at least to the minimum recrystallization temperature in less than about 60 minutes. The cold worked component blank can be maintained at least at the minimum recrystallization

20 temperature for less than about 60 minutes.

In another aspect of the invention, a sputter component forming method can include unidirectionally first cold working a component blank to at least about an 80% reduction in cross-sectional area and heat treating the cold worked component

blank at least at about a minimum recrystallization temperature of the component blank. A sufficient amount of stress may be induced in the heat treated component to increase magnetic pass through flux exhibited by the heat treated component compared to pass through flux exhibited prior to inducing the stress.

5 In a further aspect of the invention, a sputter target forming method can include unidirectionally first cold rolling a target blank consisting essentially of nickel to at least about an 85% reduction in cross-sectional area. Heat treatment of the cold rolled target blank can occur at a temperature between about 427°C (800°F) to about 482°C (900°F) for less than about 60 minutes. Second cold rolling 10 of the heat treated target blank can occur to a reduction in cross-sectional area of about 10% of the heat treated component. The second cold rolled target blank may exhibit at least about 70% of a surface area at least within selected boundaries of a surface of the second cold rolled target blank having a (200) texture.

15 In another aspect of the invention, a magnetic flux enhancement method for a sputter component includes combining unidirectional cold working of a sputter component with heat treatment at about a minimum recrystallization temperature and orienting predominant crystallographic structure preferentially at (200). The method may include additional unidirectional cold working in a same direction as initially cold worked.

20 In a still further aspect of the invention, a PVD component includes nickel exhibiting a (200) texture over at least about 50% of a surface area at least within selected boundaries and having a sufficient amount of residual stress to exhibit higher magnetic pass through flux compared to pass through flux exhibited absent

such stress. Additional aspects of the invention include PVD components or targets produced by the methods described above.

BRIEF DESCRIPTION OF THE DRAWINGS

5 Preferred embodiments of the invention are described below with reference to the following accompanying drawing.

The figure shows a chart comparing magnetic pass through flux of a sputter target according to the present invention compared to a conventional target.

10 **DETAILED DESCRIPTION OF THE PREFERRED EMBODIMENTS**

The need to reduce grain size of sputter targets and identify crystallographic orientations and magnetic properties beneficial to forming sputter films has prompted investigation of physical vapor deposition (PVD) component forming methods. Observation indicates that crystallographic orientation and magnetic 15 softness or hardness may also influence sputter film uniformity. Magnetically soft materials may attenuate the magnetic flux from a sputter apparatus cathode, focusing the magnetic field to a small portion of a sputter target. The focused field can result in a sharp, deep sputter track that accelerates burn-through and limits target life.

20 In the context of the present application, “magnetically soft” materials exhibit a tendency to lose magnetization more quickly in comparison to a “magnetically hard” material. Magnetically soft materials often can be magnetized and demagnetized readily with little or no permanent magnetization (remanence).

Generally, magnetically hard materials are more difficult to magnetize, but retain remanent magnetization. Also, a “sputter component” used in the context of the present application denotes sputter targets as well as other components in a sputter chamber that may undergo sputtering. The processing parameters described herein

5 for PVD component forming methods and magnetic flux enhancement methods pertain particularly to sputter targets containing nickel, but may also apply to PVD components of other compositions.

In one aspect of the invention, a PVD component forming method includes first cold working a component blank to at least about an 80% reduction in cross-sectional area. Next, the cold worked component blank may be heat treated at least at about a minimum recrystallization temperature of the component blank. The

10 heat treated component blank can be second cold worked to a reduction in cross-sectional area between about 5% to about 15% of the heat treated component.

The high level of first cold work may assist in reducing secondary

15 recrystallization effects that result in anomalous rapid grain growth in isolated domains. Typically, the objective of the cold working is to minimize the artifacts of pre-existing structure, such as grain size and texture, from the starting component blank. The artifacts can be merely cosmetic (swirls, ghosts, etc.) but can also be non-uniform structures in portions of the first cold worked component. It is

20 desirable to maximize uniformity by cold working and observation indicates that about 80-90% cold work can be adequate. Preferably, cross-sectional area is reduced by at least about 85% to obtain a preferred level of uniformity and minimization of artifacts.

Cold working preferably comprises cold rolling, however, extrusion, drawing, forging, and other cold working methods known to those skilled in the art may also be suitable. Also, preferably cold rolling or other cold working can be unidirectional to produce a high level of (200) crystallographic orientation. One 5 disadvantage of unidirectional cold rolling is generation of scrap material.

Conventionally, "round to round" rolling allows a higher utilization level for starting material compared to unidirectional rolling, that generates more scrap because of limitations on rolling directions.

However, unidirectional rolling provides advantageous crystallographic 10 orientation. For example, the first cold worked component blank may exhibit an orientation ratio of at least 50% (200) or, preferably, at least about 70% (200). In measuring orientation ratio, at least 50% or at least 70% of a surface area at least within selected boundaries of a surface of the first cold worked component blank may exhibit a (200) texture. Cross-rolling or "round-to-round rolling" can be 15 detrimental, even in small amounts, to obtaining a majority (200) texture. However, simple unidirectional cold rolling of a nickel sputter target blank has been observed to produce a majority (200) texture. Preferably, the component blank consists 20 essentially of nickel. However, other materials, particularly those having a face-centered cubic crystalline structure, may be suitable to achieve the advantages of the various aspects of the invention. The first cold working, as well as the second cold working, may occur at a temperature of about 20°C (68°F) or some other suitable temperature known to those skilled in the art to be considered cold working.

The heat treating may comprise substantially uniformly heating the cold worked component blank at least to the minimum recrystallization temperature in less than about 60 minutes. Such a heating step, or annealing, is desirable since lengthy, high temperature annealing is known to lead to secondary recrystallization 5 and produce the detrimental effects of PVD component microstructure described above. The heated, cold worked component blank may be maintained at least at the minimum recrystallization temperature for less than about 60 minutes.

The initial heating and maintaining the temperature may be performed in a fluidized bed furnace. Fluidized bed furnaces can impart quick and uniform heat 10 transfer to the cold worked PVD component blank. A variety of fluidized bed furnaces known to those skilled in the art may be suitable for accomplishing the heat treating described herein. A variety of heat transfer media may be used in the fluidized bed furnace, for example, alumina has proven suitable. Other fast-transfer methods, such as quartz-bulb (infrared) or electric induction furnace, may be used 15 in the place of a fluidized bed furnace to heat the PVD component blank quickly and uniformly.

After maintaining the cold worked component blank at the described temperature, the component blank may be air cooled to 20°C (68°F) or another desired temperature. Alternatively, the component blank may be quenched to a 20 temperature less than the minimum recrystallization temperature. A suitable heat treating temperature may be between about 371°C (700°F) to about 1200°C (649°F) or, preferably, between about 427°C (800°F) to about 482°C (900°F). The

range of 800°F to 900 °F is particularly suitable for a sputter target blank consisting essentially of nickel.

After heat treating, the PVD component blank preferably exhibits an average grain size of less than about 50 microns. Average grain size can be

- 5 measured by a variety of techniques, for example, one suitable technique is ASTM Test Method E112. When measuring average grain size or texture, as in a (200) texture, such measurement may occur within selected boundaries of at least a portion of a surface area of the PVD component blank. As an example, the measured area defined by the selected boundaries may include at least about a
- 10 statistically representative area. The statistically representative area may be calculated by any current or future method known to those skilled in the art. Also, it may be desirable to evaluate whether an outer surface of a specimen accurately reflects grain size or texture of the overall microstructure by removing an outer surface to expose inner portions of a specimen. An unrepresentative measurement
- 15 might skew data such that a more narrow or wide distribution of grain size or texture is calculated than would result from evaluating the entirety of measurable surfaces of a specimen. Evaluating all of the surfaces of a specimen that are conducive to the measurements indicated (i.e., measurable) may be possible. Even so, evaluating representative areas is more efficient and thus desirable. Rules of
- 20 thumb or other methods may be known in the art for selecting a representative area, in addition to Test Method E112 referenced above.

Second cold working the heat treated component blank may be used to reduce cross-sectional area to between about 5% to about 15% of the heat treated

component. The small amount of cold working after heat treatment has been observed to create a small amount of residual stress in the target and yield a relatively large increase in the magnetic flux that may pass through a PVD component blank as measured perpendicular to the blank face. The amount of 5 stress is small enough to be virtually undetectable visually and mechanically and has not been observed to degrade sputtered films formed from such a component. It appears that the induced stress alone is not sufficient to substantially alter surface grain appearance.

Preferably, the second cold working reduction in cross-sectional area is 10 about 10%. Also, preferably the second cold working comprises cold rolling and can comprise a different cold working process than used for the first cold working. The second cold working is also preferably unidirectional as described for the first cold working, but only one might be unidirectional. Preferably, the first and second cold working are both unidirectional and each are in the same direction. Working 15 in the same direction further minimizes any impact of the second cold working on desirable grain size and texture obtained from first cold working and heat treating.

Accordingly, the method of the present aspect of the invention can produce a PVD component that exhibits a (200) texture over at least about 50% of a surface area. The component may also exhibit an average grain size of less than about 50 20 microns. The grains may have an adequate amount of residual stress to enhance magnetic flux. In this manner, a PVD component will exhibit a small grain size and also exhibit a crystallographic orientation properly stressed to allow a higher pass through flux (PTF) than absent the stress, prolonging target life. Fig. 1 is a chart

showing an overall increase in PTF for a (200) nickel sputter target produced according to the present aspect of the invention in comparison to a conventional (220) nickel sputter target without induced stress.

One possible explanation for the PTF improvement of the invention in the case of nickel targets relates to the magnetostriction properties of nickel. Speaking simplistically, a magnetic field causes the face centered cubic crystalline structure of nickel to constrict. When nickel grains of a sputter target are oriented with a (200) texture, a magnetic field perpendicular to the target face produces constriction in a direction also perpendicular to the target face. A portion of the magnetic field is thus involved in the constriction, affecting PTF. Inducing stress in the target to produce constriction before exposure to a magnetic field is observed to increase PTF. It is presumed that the induced constriction reduces further constriction by the magnetic field, involving less of the magnetic field and allowing more flux.

Accordingly, in one aspect of the invention, a PVD component forming method includes inducing a sufficient amount of stress in the component to increase magnetic pass through flux exhibited by the component compared to pass through flux exhibited prior to inducing the stress. A variety of stress inducing methods other than cold working may be suitable to accomplish the method. The method may further include orienting a majority crystallographic structure of the component at (200) prior to inducing the stress, wherein the induced stress alone is not sufficient to substantially alter surface grain appearance. In this manner, beneficial characteristics of grain size and texture are largely unaffected, but PTF can be improved. It is conceivable that textures other than (200) and materials

other than nickel may also be suitable for practicing the methods described herein with analogous advantages.

In another aspect of the invention, a sputter component forming method may include unidirectionally first cold working a component blank to at least about 5 an 80% reduction in cross-sectional area. The cold worked component blank may be heat treated at least at about a minimum recrystallization temperature of the component blank. A sufficient amount of stress may be induced in the heat treated component to increase magnetic pass through flux exhibited by the heat treated component compared to pass through flux exhibited prior to inducing the stress.

10 Such a method can achieve at least some of the advantages described herein as desirable for sputter components. Inducing stress may include unidirectionally second cold working the heat treated component to a reduction in cross-sectional area between about 5% to about 15% of the heat treated component. The second cold working used in the described method may further improve the desirable 15 properties of the sputter component.

In a further aspect of the invention, a sputter target forming method can include unidirectionally first cold rolling a target blank consisting essentially of nickel to at least about an 85% reduction in cross-sectional area. The cold rolled target blank can be heat treated at a temperature between about 427°C (800°F) to 20 about 482°C (900°F) for less than about 60 minutes. The heat treated target blank can be second cold rolled to a reduction in cross-sectional area of about 10% of the heat treated component. At least about 70% of a surface area at least within

selected boundaries of a surface of the second cold rolled target blank may exhibit a (200) texture.

In another aspect of the invention, a magnetic flux enhancement method for a sputter component may include combining unidirectional cold working of a 5 sputter component with heat treatment at least at about a minimum recrystallization temperature. The method may further include orienting predominant crystallographic structure preferentially at (200) followed by additional unidirectional cold working in a same direction as initially cold worked.

In keeping with the aspects of the invention described above regarding 10 methods of forming PVD components, a PVD component in another aspect of the invention may consist essentially of nickel exhibiting a (200) texture over at least about 50% of a surface area at least within selected boundaries. As described, the selected boundaries may define a representative test area. The component may have a sufficient amount of residual stress to exhibit higher magnetic pass through 15 flux compared to pass through flux exhibited absent such stress.

In compliance with the statute, the invention has been described in language more or less specific as to structural and methodical features. It is to be understood, however, that the invention is not limited to the specific features shown and described, since the means herein disclosed comprise preferred forms of 20 putting the invention into effect. The invention is, therefore, claimed in any of its forms or modifications within the proper scope of the appended claims appropriately interpreted in accordance with the doctrine of equivalents.

CLAIMS

1. A physical vapor deposition (PVD) component forming method comprising inducing a sufficient amount of stress in the component to increase magnetic pass through flux exhibited by the component compared to pass through flux exhibited prior to inducing the stress.

2. The method of claim 1 wherein the inducing a sufficient amount of stress comprises cold working to a reduction in cross-sectional area between about 5% to about 15%.

3. The method of claim 1 further comprising orienting a majority 10 crystallographic structure of the component at (200) prior to inducing the stress, wherein the induced stress alone is not sufficient to substantially alter surface grain appearance.

4. The method of claim 3 wherein the orienting the majority crystallographic structure comprises cold working a component blank to at least 15 about an 80% reduction in cross-sectional area followed by heat treating at least at about a minimum recrystallization temperature of the component blank.

5. The method of claim 4 wherein the reduction in cross-sectional area is at least about 85%.

6. The method of claim 1 wherein the component exhibits a (200) texture 20 over at least about 50% of a surface area at least within selected boundaries.

7. The method of claim 1 wherein the component exhibits an average grain size of less than 50 microns.
8. The method of claim 1 wherein the component consists essentially of a material having a face-centered cubic crystalline structure.

5 9. The method of claim 1 wherein the component consists essentially of nickel.

10. A PVD component forming method comprising:

first cold working a component blank to at least about an 80% reduction in

cross-sectional area;

heat treating the cold worked component blank at least at about a minimum

5 recrystallization temperature of the component blank; and

second cold working the heat treated component blank to a reduction in

cross-sectional area between about 5% to about 15% of the heat treated

component.

11. The method of claim 10 wherein the second cold worked component

10 blank exhibits a (200) texture over at least about 50% of a surface area at least

within selected boundaries.

12. The method of claim 11 wherein the second cold worked component

blank exhibits a (200) texture over at least about 70% of the surface area.

13. The method of claim 10 wherein at least one of the first and second cold

15 working comprises cold rolling.

14. The method of claim 10 wherein the component blank comprises a

sputter target blank.

15. The method of claim 10 wherein the component blank consists essentially

of nickel.

16. The method of claim 10 wherein the first and second cold working occur at about 20 °C (68 °F).

17. The method of claim 10 wherein at least one of the first and second cold working is unidirectional.

5 18. The method of claim 10 wherein the first and second cold working are both unidirectional and each in a same direction.

19. The method of claim 10 wherein the heat treating comprises:
substantially uniformly heating the cold worked component blank at least to the minimum recrystallization temperature in less than about 60 minutes; and
10 maintaining the cold worked component blank at least at the minimum recrystallization temperature for less than about 60 minutes.

20. The method of claim 10 wherein the heat treating is performed with a fluidized bed furnace.

21. The method of claim 10 wherein the heat treating occurs between about 15 371 °C (700 °F) to about 649 °C (1200 °F).

22. The method of claim 21 wherein the heat treating occurs between about 427 °C (800 °F) to about 482 °C (900 °F).

23. The method of claim 10 wherein the second cold working reduction in cross-sectional area is about 10%.

24. A sputter component forming method comprising:

unidirectionally first cold working a component blank to at least about an 80% reduction in cross-sectional area;

heat treating the cold worked component blank at least at about a minimum 5 recrystallization temperature of the component blank; and

inducing a sufficient amount of stress in the heat treated component to increase magnetic pass through flux exhibited by the heat treated component compared to pass through flux exhibited prior to inducing the stress.

25. The method of claim 24 wherein inducing the stress comprises

10 unidirectionally second cold working the heat treated component blank to a reduction in cross-sectional area between about 5% to about 15% of the heat treated component.

26. A sputter target forming method comprising:
unidirectionally first cold rolling a target blank consisting essentially of
nickel to at least about an 85% reduction in cross-sectional area;
heat treating the cold rolled target blank at a temperature between about
5 427 °C (800 °F) to about 482 °C (900 °F) for less than about 60 minutes; and
second cold rolling the heat treated target blank to a reduction in cross-
sectional area of about 10% of the heat treated component, at least about 70% of a
surface area at least within selected boundaries of a surface of the second cold
rolled target blank exhibiting a (200) texture.

27. A magnetic flux enhancement method for a sputter component comprising combining unidirectional cold working of a sputter component with heat treatment at least at about a minimum recrystallization temperature and orienting predominate crystallographic structure preferentially at (200) followed by 5 additional unidirectional cold working in a same direction as initially cold worked.

28. A PVD component produced by the method of claim 1.

29. A sputter component produced by the method of claim 24.

30. A sputter target produced by the method of claim 26.

31. A PVD component consisting essentially of nickel exhibiting a (200) texture over at least about 50% of a surface area at least within selected boundaries and having a sufficient amount of residual stress to exhibit higher magnetic pass through flux compared to pass through flux exhibited absent such stress.

5 32. The component of claim 31 wherein the selected boundaries define a representative test area.

33. The component of claim 31 wherein the metal exhibits an average grain size of less than about 50 microns.

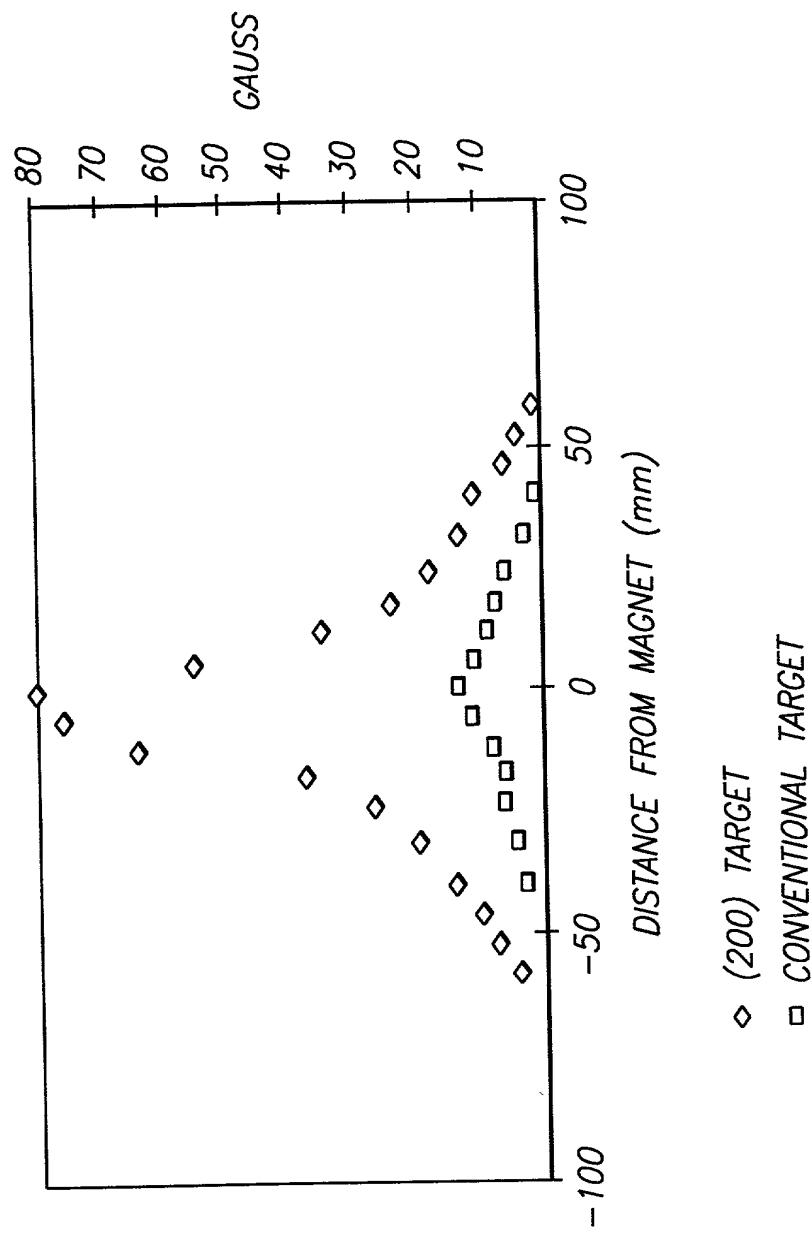
ABSTRACT OF THE DISCLOSURE

A PVD component forming method includes inducing a sufficient amount of stress in the component to increase magnetic pass through flux exhibited by the component compared to pass through flux exhibited prior to inducing the stress.

5 The method may further include orienting a majority crystallographic structure of the component at (200) prior to inducing the stress, wherein the induced stress alone is not sufficient to substantially alter surface grain appearance. Orienting structure may include first cold working a component blank to at least about an 80% reduction in cross-sectional area. The cold worked component blank can be

10 heat treated at least at about a minimum recrystallization temperature of the component blank. Inducing stress may include second cold work to a reduction in cross-sectional area between about 5% to about 15% of the heat treated component. At least one of the first and second cold working can be unidirectional.

1/1



HW Docket No.: H0001190(4016)

EL465852649US

**DECLARATION FOR PATENT APPLICATION
SOLE OR JOINT**

As a below named inventor, I hereby declare that:

My residence, post office address and citizenship are as stated below next to my name.

I believe I am the original, first and sole inventor (if only one name is listed below) or an original, first and joint inventor (if plural names are listed below) of the subject matter which is claimed and for which a patent is sought on the invention titled:

Physical Vapor Deposition Components and Method of Formation

the specification of which is attached hereto unless the following box is checked.

was filed on _____ as United States Application Number or PCT International Application Number _____ and was amended on _____ (If Applicable).

I HEREBY STATE THAT I HAVE REVIEWED AND UNDERSTAND THE CONTENTS OF THE ABOVE-IDENTIFIED SPECIFICATION, INCLUDING THE CLAIMS

I ACKNOWLEDGE THE DUTY TO DISCLOSE INFORMATION THAT IS MATERIAL TO THE PATENTABILITY OF THIS APPLICATION IN ACCORDANCE WITH TITLE 37, CODE OF FEDERAL REGULATIONS, §1.56(a).

I hereby claim foreign priority benefits under Title 35, United States Code, §119 of any foreign application(s) for patent or inventor's certificate listed below and have also identified below any foreign application for patent or inventor's certificate having a filing date before that of the application on which priority is claimed.

Prior Foreign Application(s)

Priority Claimed

Yes No

Yes No

Yes No

I hereby claim the benefit under Title 35, United States Code, §120 of any United States applications listed below and, INsofar AS THE SUBJECT MATTER OF EACH OF THE CLAIMS OF THIS APPLICATION IS NOT DISCLOSED IN THE PRIOR UNITED STATES APPLICATION IN THE MANNER PROVIDED BY THE FIRST PARAGRAPH OF TITLE 35, UNITED STATES CODE, §112, I ACKNOWLEDGE THE DUTY TO DISCLOSE MATERIAL INFORMATION AS DEFINED IN TITLE 37, CODE OF FEDERAL REGULATIONS, §1.56(a) WHICH OCCURRED BETWEEN THE FILING DATE OF THE PRIOR APPLICATION AND THE NATIONAL OR PCT INTERNATIONAL FILING DATE OF THIS APPLICATION.

(Application Serial Number)	(Filing Date)	(STATUS: Patented, Pending, Abandoned)
(Application Serial Number)	(Filing Date)	(STATUS: Patented, Pending, Abandoned)

SEND CORRESPONDENCE TO:

Shannon Morris

Honeywell International Inc

P.O. Box 2245

101 Columbia Road, Morristown, New Jersey 07962

DIRECT TELEPHONE CALLS TO:

(724) 452-1523

DECLARATION FOR PATENT APPLICATION—SOLE OR JOINT (Continued)

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code, and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon

FULL NAME OF SOLE OR FIRST INVENTOR Matthew S. Cooper Date 10/26/00
INVENTOR'S SIGNATURE Matthew S. Cooper
RESIDENCE Portersville, Pennsylvania
CITIZENSHIP US
POST OFFICE ADDRESS 103 E. Portersville Road
Portersville, PA 16051

FULL NAME OF SECOND JOINT INVENTOR _____ Date _____
INVENTOR'S SIGNATURE _____
RESIDENCE _____
CITIZENSHIP _____
POST OFFICE ADDRESS _____

FULL NAME OF THIRD JOINT INVENTOR _____ Date _____
INVENTOR'S SIGNATURE _____
RESIDENCE _____
CITIZENSHIP _____
POST OFFICE ADDRESS _____

FULL NAME OF FOURTH JOINT INVENTOR _____ Date _____
INVENTOR'S SIGNATURE _____
RESIDENCE _____
CITIZENSHIP _____
POST OFFICE ADDRESS _____

FULL NAME OF FIFTH JOINT INVENTOR _____ Date _____
INVENTOR'S SIGNATURE _____
RESIDENCE _____
CITIZENSHIP _____
POST OFFICE ADDRESS _____

FULL NAME OF SIXTH JOINT INVENTOR _____ Date _____
INVENTOR'S SIGNATURE _____
RESIDENCE _____
CITIZENSHIP _____
POST OFFICE ADDRESS _____

FULL NAME OF SEVENTH JOINT INVENTOR _____ Date _____
INVENTOR'S SIGNATURE _____
RESIDENCE _____
CITIZENSHIP _____
POST OFFICE ADDRESS _____

DECLARATION FOR PATENT APPLICATION--SOLE OR JOINT (Continued)

Attorney Docket No. H0001190(4016)-Page 3

POWER OF ATTORNEY: As a named inventor, I hereby appoint the following attorney(s) and/or agent(s) to prosecute this application and transact all business in the Patent and Trademark Office connected herewith (List name and registration number).

(LIST SENIOR PATENT COUNSEL AND ATTORNEY HANDLING CASE WITH PATENT OFFICE REGISTRATION NUMBERS.)

Mary Ann Lemere

Shannon Morris

Curt Brueske

Name

Name

Name

32,160

42,909

33,839

Registration Number

Registration Number

Registration Number

David P. Roberts

Randy A. Gregory

Deepak Malhotra

Name

Name

Name

23,032

30,386

33,560

Registration Number

Registration Number

Registration Number

Mark S. Matkin

James L. Price

George G. Grigel

Name

Name

Name

32,268

27,376

31,166

Registration Number

Registration Number

Registration Number

Mark Hendrickson

David G. Latwesen, Ph.D.

Frederick M. Fliegel

Name

Name

Name

32,356

38,533

36,138

Registration Number

Registration Number

Registration Number

Keith D. Grzelak

James D. Shaureite

Bernard Berman

Name

Name

Name

37,144

39,833

37,279

Registration Number

Registration Number

Registration Number

D. Brent Kenady

James E. Lake

Name

Name

Name

40,045

44,854

Registration Number

Registration Number

Registration Number

Registration Number

Name

Name

Name

Registration Number

Registration Number

Registration Number

Name

Name

Name

Registration Number

Registration Number

Registration Number

Name

Name

Name

Registration Number

Registration Number

Registration Number